

Power Supply IC Series for TFT-LCD Panels

High-precision Gamma Correction ICs with built-in DAC

BD8132FV, BD8139AEFV

No.09035EBT02

Description

These gamma correction voltage generation ICs feature built-in DACs and provide a single-chip solution with setting control via serial communications, a high-precision 10-bit DAC, an output amp (18-channel or 10-channel), and Vcom.

Features

- 1) Single-chip design means fewer components
- 2) Built-in 10 bit DAC (18ch: BD8132FV, 10ch: BD8139AEFV)
- 3) Built-in DAC output amp
- 4) Built-in Vcom amp
- 5) Built-in auto-read function
- 6) 3-line serial interface (BD8132FV) or 2-wire serial (BD8139AEFV)
- 7) Thermal shutdown circuit
- 8) SSOP-B40 package (BD8132FV) / HTSSOP-B40 package (BD8139AEFV)

Applications

These ICs can be used with TFT LCD panels used by large-screen and high-definition LCD TVs.

Absolute maximum ratings (Ta = 25°C)

| Parame | ter | Symbol | Limit | Unit |
|------------------------------|----------|--------|-------------|------|
| Power supply voltage 1 | | DVcc | 7 | V |
| Power supply voltage 2 | | Vcc | 20 | V |
| REFIN voltage | | REF | 20 | V |
| Amp output current capa | city | lo | 50*1 | mA |
| Junction temperature | | Tjmax | 150 | °C |
| Dower dissinction | BD8132FV | - Pd | 1125*2 | mW |
| Power dissipation BD8139AEFV | | Pu | 1600*3 | mvv |
| Operating temperature ra | ange | Topr | -30 to +85 | °C |
| Storage temperature ran | ge | Tstg | -55 to +150 | °C |

*1 Must not exceed Pd.

*2 Reduced by 9.0 mW/°C over 25°C, when mounted on a glass epoxy board (70 mm × 70 mm × 1.6 mm).

*3 Reduced by 12.8 mW/°C over 25°C, when mounted on a glass epoxy board (70 mm × 70 mm × 1.6 mm).

Recommended Operating Ranges

| Parameter | Symbol | Li | mit | Unit |
|--------------------------------------|--------|------|------|------|
| Faidifielei | Symbol | Min. | Max. | Unit |
| Power supply voltage 1 | DVcc | 2.3 | 4.0 | V |
| Power supply voltage 2 | Vcc | 6 | 18 | V |
| REFIN voltage | REF | 6 | 18 | V |
| Amp output current capacity | lo | — | 40 | mA |
| Serial clock frequency (BD8132FV) | fCLK | — | 5 | MHz |
| 2 wire serial frequency (BD8139AEFV) | fCLK | — | 400 | kHz |
| OSC frequency (BD8132FV) | fosc | 10 | 200 | kHz |
| OSC frequency (BD8139AEFV) | fosc | — | 400 | kHz |

•Electrical Characteristics

BD8132FV(Unless otherwise specified, Vcc = 15 V, DVcc = 3.3 V, Ta = 25°C)

| Parameter | Symbol | | Limit | | Unit | Condition |
|------------------------------|------------|----------|---------|------|------|---|
| Falameter | Symbol | Min. | Тур. | Max. | Unit | Condition |
| [REFIN] | | | | | | |
| Sinking current | Iref | 25 | 50 | 75 | μA | REF = 10 V |
| [Gamma correction amp block] | | | | | | |
| Output current capacity | lo | 150 | 300 | — | mA | DAC = 3V, OUTx = 0 V |
| Load stability | ΔV | — | 5 | 20 | mV | Io = +10 mA to -10 mA, OUTx = 6 V |
| Slew rate | SR | — | 3.5 | — | V/µS | Ro = 100 k Ω , Co = 100 pF * |
| OUT max. output voltage | VOH | Vcc-0.16 | Vcc-0.1 | — | V | lo = -5 mA |
| OUT min. output voltage | VOL | — | 0.15 | 0.24 | V | lo = 5 mA |
| [Common amp block] | | | | | | |
| Input bias current | lb | | 0 | 1 | μA | VFB = 6 V |
| Output current capacity | lo | 150 | 300 | | mA | DAC = 3V, OUTx = 0 V |
| Load stability | ΔV | | 5 | 20 | mV | lo = +10 mA to -10 mA, OUTx = 3 V |
| Slew rate | SR | | 3.5 | _ | V/µS | Ro = 100 kΩ, Co = 100 pF * |
| Input voltage range | VFB | 0 | | VDAC | V | Ro = 100 kΩ, Co = 100 pF * |
| OUT max. output voltage | VOH | Vcc-0.16 | Vcc-0.1 | | V | lo = -5 mA |
| OUT min. output voltage | VOL | | 0.15 | 0.24 | V | lo = 5 mA |
| [DAC] | | | | | | |
| Resolution | Res | | 10 | | Bit | |
| Nonlinearity error | LE | -2 | _ | 2 | LSB | Ideal line error: 00A to 3F5 |
| Differential linearity error | DLE | -2 | _ | 2 | LSB | 1 LSB ideal increase error: 00A to 3F5 |
| [OSC] | 4 | | | | 4 | · |
| Oscillating frequency | fosc | | 80 | | kHz | Internal frequency mode |
| [Control signals] | | | | | | |
| Sinking current | Ictl | | 16 | 25 | μA | |
| Threshold voltage | VTH | 0.7 | | 2.6 | V | DVCC = 3.3 V |
| Reset time | trst | — | 45 | | μs | CCT = 1000 pF |
| [Overall] | · | | | | ÷ | · |
| Total supply current | lcc | — | 20 | | mA | When all output voltages are set to 5 V |

•Electrical Characteristics

BD8139AEFV (Unless otherwise specified, Vcc = 15 V, DVcc = 3.3 V, Ta = 25°C)

| | | , | Limit | , | Í | |
|------------------------------|--------|----------|---------|------|------|---|
| Parameter | Symbol | Min. | Тур. | Max. | Unit | Condition |
| [REFIN] | 1 | 1 | | | | |
| Sinking current | Iref | 25 | 50 | 75 | μA | REF = 10V |
| [Gamma correction amp block] | | | | | | |
| Output current capacity | lo | 150 | 300 | _ | mA | DAC = 3 V, OUTx = 0 V |
| Load stability | ΔV | | 5 | 20 | mV | lo = +10 mA to -10 mA, OUTx = 6 V |
| Slew rate | SR | _ | 3.5 | _ | V/µs | Ro = 100 kΩ, Co = 100 pF * |
| OUT max. output voltage | VOH | Vcc-0.16 | Vcc-0.1 | | V | lo = -5 mA |
| OUT min. output voltage | VOL | _ | 0.1 | 0.16 | V | lo = 5 mA |
| [Common amp block] | | | | | | |
| Input bias current | lb | — | 0 | 1 | μA | VFB = 6 V |
| Output current capacity | lo | 150 | 300 | | mA | DAC = 3 V, OUTx = 0 V |
| Load stability | ΔV | | 5 | 20 | mV | Io = +10 mA to -10 mA, OUTx = 3 V |
| Slew rate | SR | | 3.5 | | V/µS | Ro = 100 kΩ, Co = 100 pF * |
| Input voltage range | VFB | 0 | _ | VDAC | V | Ro = 100 kΩ, Co = 100 pF * |
| OUT max. output voltage | VOH | Vcc-0.16 | Vcc-0.1 | _ | V | lo = -5 mA |
| OUT min. output voltage | VOL | | 0.1 | 0.16 | V | lo = 5 mA |
| [DAC] | | | | | | |
| Resolution | Res | _ | 10 | | Bit | |
| Nonlinearity error | LE | -2 | _ | 2 | LSB | Ideal line error: 00A to 3F5 |
| Differential linearity error | DLE | -2 | | 2 | LSB | 1 LSB ideal increase error: 00A to 3F5 |
| [OSC] | | | | | | |
| Oscillating frequency | fosc | _ | 210 | | kHz | Internal frequency mode |
| [Control signals] | | | | | | |
| Sinking current | lctl | _ | 16 | 25 | μA | Except for osc_mode |
| Sinking current | loscm | 26 | 33 | 40 | μA | Only osc_mode |
| Min. output voltage | VSDA | — | _ | 0.4 | V | ISDA = 3.0 mA * |
| Sinking current | ILi | -10 | _ | 10 | μA | 0.4 V to 0.9 V DVCC |
| Threshold voltage | VTH | 0.7 | _ | 2.6 | V | DVCC = 3.3 V |
| Reset time | trst | | 45 | | μs | CCT = 1000 pF |
| [Overall] | | | | | | · |
| Total supply current | lcc | | 18 | _ | mA | When all output voltages are set to 5 V |

Reference Data

(Unless otherwise specified, Ta = 25°C, BD8132FV and BD8139AEFV)

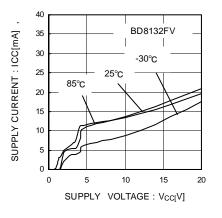


Fig. 1 Vcc Total Supply Current

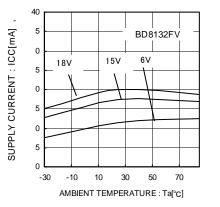


Fig. 2 Total Supply Current vs Temperature

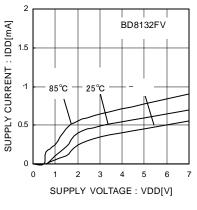


Fig. 3 VDD Total Supply Current

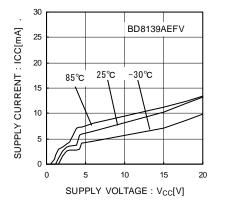
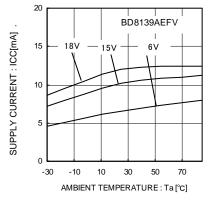
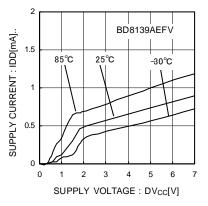
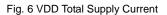


Fig. 4 Vcc Total Supply Current









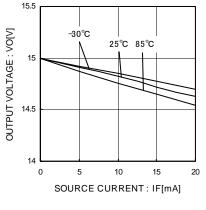


Fig. 7 High Output Voltage

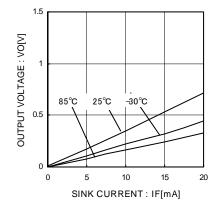
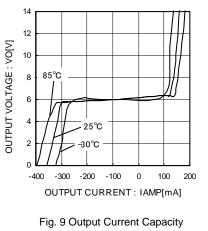
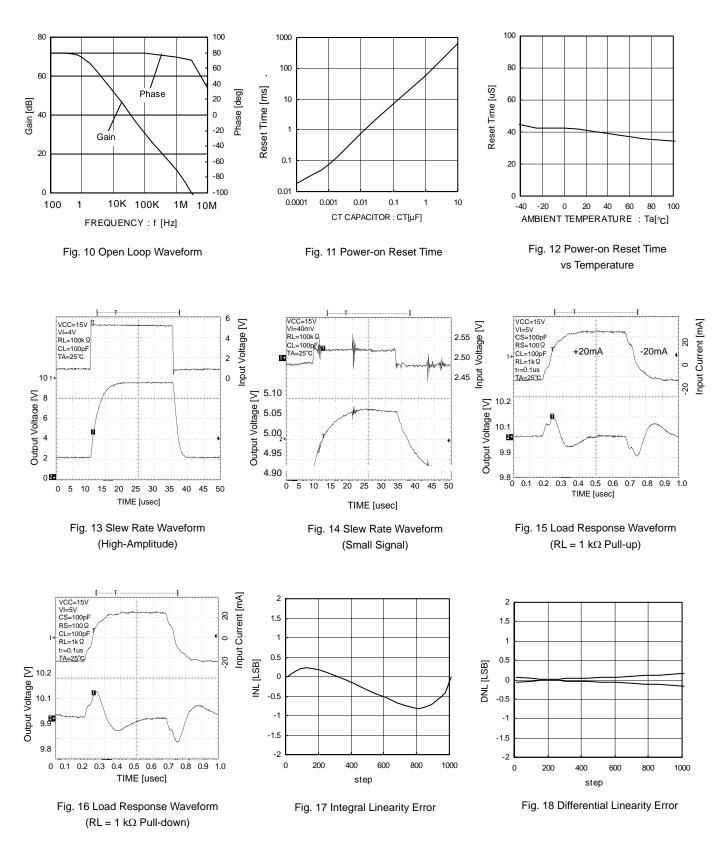


Fig. 8 Low Output Voltage

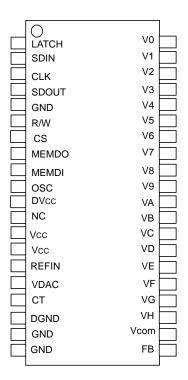


Reference Data

(Unless otherwise specified, Ta = 25°C, BD8132FV and BD8139AEFV)



●Pin Assignment Diagram [BD8132FV]



Block Diagram

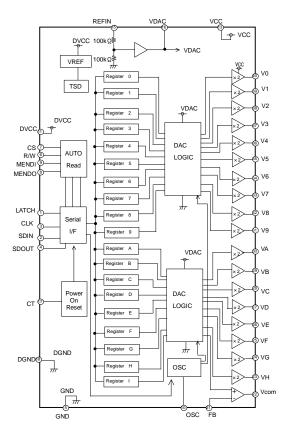


Fig. 19 Pin Assignment Diagram & Block Diagram

| PIN N | ame and Fi | unction | | | |
|------------|-------------|---|------------|-------------|----------------------------------|
| Pin No. | Pin name | Function | Pin No. | Pin name | Function |
| 1 | LATCH | Serial latch input | 21 | FB | Vcom amp negative feedback input |
| 2 | SDIN | Serial data input | 22 | Vcom | Vcom output pin |
| 3 | CLK | Serial clock input | 23 | VH | Gamma correction output pin |
| 4 | SDOUT | Serial data output | 24 | VG | Gamma correction output pin |
| 5 | GND | GND input | 25 | VF | Gamma correction output pin |
| 6 | R/W | Auto-read on/off input (On = Low, Off = High) | 26 | VE | Gamma correction output pin |
| 7 | CS | External memory selection output | 27 | VD | Gamma correction output pin |
| 8 | MEMDO | External memory output data signal | 28 | VC | Gamma correction output pin |
| 9 | MEMDI | External memory input data signal | 29 | VB | Gamma correction output pin |
| 10 | OSC | Tuning clock I/O | 30 | VA | Gamma correction output pin |
| 11 | DVcc | Logic power supply input | 31 | V9 | Gamma correction output pin |
| 12 | NC | — | 32 | V8 | Gamma correction output pin |
| 13 | Vcc | Buffer amp power supply input | 33 | V7 | Gamma correction output pin |
| 14 | Vcc | Buffer amp power supply input | 34 | V6 | Gamma correction output pin |
| 15 | REFIN | DAC reference input | 35 | V5 | Gamma correction output pin |
| 16 | VDAC | DAC voltage output | 36 | V4 | Gamma correction output pin |
| 17 | СТ | Power-on reset capacitance connection pin | 37 | V3 | Gamma correction output pin |
| 18 | DGND | DAC GND input | 38 | V2 | Gamma correction output pin |
| 19 | GND | GND input | 39 | V1 | Gamma correction output pin |
| 20 | GND | GND input | 40 | V0 | Gamma correction output pin |

Pin Name and Function

Pin Assignment Diagram Block Diagram [BD8139AEFV] REFIN VDAC Vcc Ο -- Vcc GND 100kΩ ₹ A1 > VDAC DVcc NC A2 100kΩ ≹ VCC NC ×2 NC VREF V0 Register 0 OSC NC Register 1 ×2 V1 SLAVE/AR V0 TSD OSC_MODE V1 VDAC ×2 V2 Register 2 SDA V2 ×2 V3 Register 3 DVcc V3 SCL x 2 A1 DAC V4 Register 4 V4 DGND A2 LOGIC ×2) V5 DACGND V5 Register 5 2wire SCL NC V6 serial I/F ×2 V6 SDA Register 6 NC V7 SLAVE/AR(×2 9) V7 Register 7 СТ V8 $\frac{1}{2}$ ×2 ₿V8 Register 8 DVcc V9 Power NC ×2 うv9 VCOM Register 9 On СТ REFIN FB Reset ₽ Register A Vcom NC NC OSC DGND Vcc FB DGND NC NC $\frac{1}{2}$ VDAC DACGND GND DACGND NC NC 7 ₫. GND OSC_MODE OSC

Fig. 20 Pin Assignment Diagram & Block Diagram

•Pin Name and Function

| - | Pin | Pin | Function | Pin | Pin | Function |
|---|-----|----------|---|-----|------|----------------------------------|
| N | lo. | name | i dilotori | No. | name | i unotori |
| | 1 | A1 | Slave/address setting pin Auto-read/word address setting pin (1) | 21 | NC | _ |
| | 2 | A2 | Slave/address setting pin Auto-read/word address setting pin (2) | 22 | NC | — |
| | 3 | NC | _ | 23 | Vcc | Buffer amp power supply input |
| | 4 | OSC | Tuning clock I/O | 24 | NC | |
| : | 5 | SLAVE/AR | Slave/auto-read selection pin | 25 | FB | Vcom amp negative feedback input |
| | 6 | OSC_MODE | OSC switching pin | 26 | Vcom | Vcom output pin |
| | 7 | SDA | Serial data input (2 wire serial) | 27 | V9 | Gamma correction output pin 9 |
| | 8 | SCL | Serial clock input (2 wire serial) | 28 | V8 | Gamma correction output pin 8 |
| | 9 | DGND | GND input | 29 | V7 | Gamma correction output pin 7 |
| 1 | 0 | DACGND | DAC GND input | 30 | V6 | Gamma correction output pin 6 |
| 1 | 11 | NC | — | 31 | V5 | Gamma correction output pin 5 |
| 1 | 12 | NC | _ | 32 | V4 | Gamma correction output pin 4 |
| 1 | 3 | СТ | Power-on reset capacitance connection pin | 33 | V3 | Gamma correction output pin 3 |
| 1 | 4 | DVcc | Logic power supply input | 34 | V2 | Gamma correction output pin 2 |
| 1 | 5 | NC | _ | 35 | V1 | Gamma correction output pin 1 |
| 1 | 6 | REFIN | DAC reference input | 36 | V0 | Gamma correction output pin 0 |
| 1 | 17 | NC | _ | 37 | NC | — |
| 1 | 8 | NC | | 38 | NC | — |
| 1 | 9 | VDAC | DAC voltage output | 39 | NC | — |
| 2 | 20 | NC | | 40 | GND | GND input |

Block Operation

VDAC Amp

The VDAC Amp amplifies the voltage applied to REFIN by 0.5x and outputs it to the VDAC pin. Connect a 1 µF phase compensation capacitor to the VDAC pin.

- DAC LOGIC
- The DAC LOGIC converts the 10-bit digital signal read to the register to a voltage.
- Amp

The Amp amplifies the voltage output from the DAC LOGIC by 2x. Input includes a sample and hold function and is refreshed by the OSC.

• OSC

The OSC generates the frequency that determines the Amp's refresh time.

External input can be selected using serial input. (For the BD8139AEFV, external input is selected using the external pin.) • Power On Reset

When the digital power supply DVCC is activated, each IC generates a reset signal to initialize the serial interface, auto-read functionality, and registers.

Adding a 1,000 pF capacitor to the CT pin ensures that reset operation can be performed reliably, without regard to the speed with which the power supply starts up.

TSD (Thermal Shut Down)

The TSD circuit turns output off when the chip temperature reaches or exceeds approximately 175°C in order to prevent thermal destruction or thermal runaway. When the chip returns to a specified temperature, the circuit resets. The TSD circuit is designed only to protect the IC itself. Application thermal design should ensure operation of the IC below the thermal shutdown detection temperature of approximately 175°C.

Register

A serial signal (consisting of 10-bit gamma correction voltage values) input using the serial interface or I²C bus interface is held for each register address. Data is initialized by the reset signal generated during a power-on reset.

Serial I/F(BD8132FV)

The serial interface uses a 3-line serial data format (LATCH, CLK, SDIN). It is used to set gamma correction voltages, specify register addresses, and select OSC I/O.

2 wire serial I/F(BD8139AEFV)

The serial interface uses a 2-line serial data format (SCL, SDA). It is used to set gamma correction voltages and specify register addresses.

Autoread

The BD8132FV uses the R/W, CLK, CS, and MEMDO pins to enable automatic reading of the IC's 1 kbit microwire type external memory.

The BD8139AEFV uses the SCL and SDA pins to enable automatic reading of the 2 wire serial bus format external memory.

[BD8132FV]

Serial communications

The serial data control block consists of a register that stores data from the LATCH, CLK, and SDIN pins, and a DAC circuit that receives the output from this register and provides adjusted voltages to other IC blocks.

When the IC's power supply is activated, the reset function operates to set the register to a preset value. The first bit is for testing use only and should always be set to 0. The next bit is used to select the OSC mode. Inputting a value of 0 selects internal frequency mode and uses a frequency of 80 kHz. Entering a value of 1 selects external frequency mode. Input an external clock signal from the OSC pin.

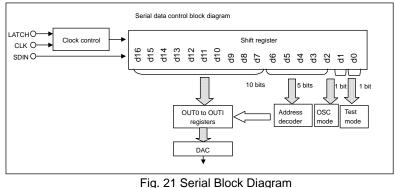


Fig. 21 Serial B

(1) Serial communications timing

The 17-bit serial data input from the SDIN pin is read into the shift register using the rising edge of the signal input to the CLK pin. This data is then loaded to the DAC register using the rising edge of the signal input to the LATCH pin. If the data loaded into the shift register while the LATCH pin is low consists of less than 17 bits, the loaded data is discarded. If the data exceeds 17 bits, the last 17 bits to be loaded are treated as valid.

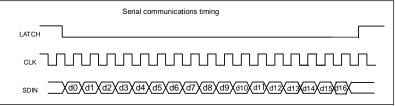


Fig. 22 Serial Communications Timing Chart

(2) Serial data

The following table illustrates the format of serial data input to the SDIN pin.

 $First \rightarrow$

| d0 d1 d2 d3 d4 d5 d6 d7 d8 d9 d10 d11 d12 d13 d14 d15 d16 0 X Register address EVALUATION | | | | | | | | | | | | | | | |
|---|----|----------------------|----|--|----|----|----|----|----|-----|-----|-----|-----|-----|------|
| 0 X Register address Data | d0 | d1 | uz | | d4 | d5 | d6 | d8 | d9 | d10 | d11 | 012 | d13 | d14 | d16 |
| | 0 | 0 X Register address | | | | | | | | Da | ata | | | | |

| Deviator | | | Addres | SS | | Debewier when dete increases | Pr | eset val | ue |
|------------|----|----|--------|----|----|------------------------------|-------|----------|-------|
| Register | d2 | d3 | d4 | d5 | d6 | Behavior when data increases | d7 | to | d16 |
| Register 0 | 0 | 0 | 0 | 0 | 0 | V0 voltage value increases | 00000 | | 00000 |
| Register 1 | 0 | 0 | 0 | 0 | 1 | V1 voltage value increases | 00000 | | 00000 |
| Register 2 | 0 | 0 | 0 | 1 | 0 | V2 voltage value increases | 00000 | | 00000 |
| Register 3 | 0 | 0 | 0 | 1 | 1 | V3 voltage value increases | 00000 | | 00000 |
| Register 4 | 0 | 0 | 1 | 0 | 0 | V4 voltage value increases | 00000 | | 00000 |
| Register 5 | 0 | 0 | 1 | 0 | 1 | V5 voltage value increases | 00000 | | 00000 |
| Register 6 | 0 | 0 | 1 | 1 | 0 | V6 voltage value increases | 00000 | | 00000 |
| Register 7 | 0 | 0 | 1 | 1 | 1 | V7 voltage value increases | 00000 | | 00000 |
| Register 8 | 0 | 1 | 0 | 0 | 0 | V8 voltage value increases | 00000 | | 00000 |
| Register 9 | 0 | 1 | 0 | 0 | 1 | V9 voltage value increases | 00000 | | 00000 |
| Register A | 0 | 1 | 0 | 1 | 0 | VA voltage value increases | 00000 | | 00000 |
| Register B | 0 | 1 | 0 | 1 | 1 | VB voltage value increases | 00000 | | 00000 |
| Register C | 0 | 1 | 1 | 0 | 0 | VC voltage value increases | 00000 | | 00000 |
| Register D | 0 | 1 | 1 | 0 | 1 | VD voltage value increases | 00000 | | 00000 |
| Register E | 0 | 1 | 1 | 1 | 0 | VE voltage value increases | 00000 | | 00000 |
| Register F | 0 | 1 | 1 | 1 | 1 | VF voltage value increases | 00000 | | 00000 |
| Register G | 1 | 0 | 0 | 0 | 0 | VG voltage value increases | 00000 | | 00000 |
| Register H | 1 | 0 | 0 | 0 | 1 | VH voltage value increases | 00000 | | 00000 |
| Register I | 1 | 0 | 0 | 1 | 0 | Vcom voltage value increases | 00000 | | 00000 |

→Last

Auto-read function

The auto-read function enables the IC's 1 kbit microwire type external memory to be automatically read.

This block operates in synchronization with the external input CLK's falling edge to output the external memory chip select signal CS as well as the memory read data signal MEMDO.

The read data signal consists of a start bit for the external memory, a read code, and a read address. When this signal is sent to the external memory, the memory outputs the data corresponding to the indicated address. Data output from the memory is read from the MEMDI pin, and this block automatically generates the serial DATA and LATCH signals and writes the memory data to the register. Memory reads are synchronized to the CLK's falling edge.

Read addresses start from address 00H and repeat until address 12H, so data must be stored from address 00H to address 12H. The auto-read function is controlled using the R/W signal. Read access to the external memory is performed continuously while the R/W signal is low. To access the external memory from another device, the R/W signal must be set to high. When the R/W signal is set to high, the CS and MEMDO pins enter a high-impedance state.

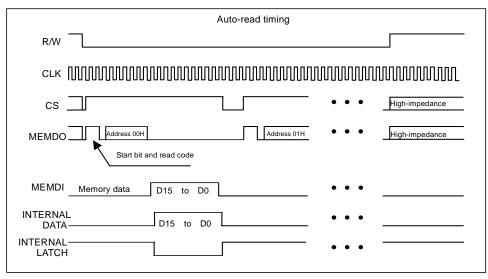


Fig. 23 Auto-read Timing Chart

| MSB | External memory data format LSB | | | | | | | | | | | |
|-------------|---|---|--|--|--|--|--|--|--|--|--|--|
| D15 | D14 | D14 D13 D12 D11 D10 D9 D8 D7 D6 D5 D4 D3 D2 D1 D0 | | | | | | | | | | |
| d1 | d2 d3 d4 d5 d6 d7 d8 d9 d10 d11 d12 d13 d14 d15 d16 | | | | | | | | | | | |
| OSC mode | Register address DAC data | | | | | | | | | | | |

Fig. 24 External Memory Data Table

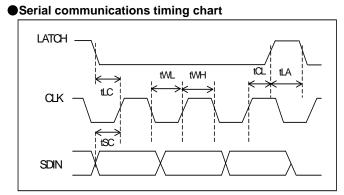
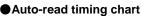


Fig.25



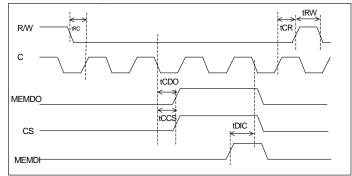


Fig.26

Timing standard values

| Parameter | Sympol | | Limit | | Unit |
|------------------|--------|------|-------|------|------|
| Parameter | Symbol | Min. | Тур. | Max. | Unit |
| Latch setup time | tLC | 0.1 | _ | — | μs |
| SDIN setup time | tSC | 0.1 | — | — | μs |
| RW setup time | tRC | 0.1 | _ | — | μs |
| MEMDI setup time | tDIC | 0.1 | _ | — | μs |
| Clock high time | tWH | 0.1 | _ | — | μs |
| Clock low time | tWL | 0.1 | _ | — | μs |
| Latch hold time | tCL | 0.1 | _ | — | μs |
| RW hold time | tCR | 0.1 | _ | — | μs |
| LATCH high time | tLA | 0.6 | _ | — | μs |
| RW high time | tRW | 0.6 | _ | — | μs |
| MEMDO delay time | tCDO | _ | — | 0.1 | μs |
| CS delay time | tCCS | — | _ | 0.1 | μs |

Gamma correction output setting (BD8132FV and BD8139AEFV)

Equation (1) describes the relationship between the gamma correction output voltage (V0 to VH) and the DAC setting. Output voltage (V0 to VH) = [(DAC setting + 1) / 1,024] × (REFIN / 2) × 2 (1)

The Vcom voltage can be set by attaching resistor R1 between the Vcom and FB pins and resistor R2 between the FB and GND pins.Equation (2) describes the relationship between the Vcom voltage and the DAC setting when using these resistors. Output voltage (Vcom) = $[(DAC \text{ setting } + 1) / 1,024] \times (REFIN / 2) \times (R1 + R2) / R2$ (2)

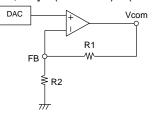


Fig. 27 Vcom Voltage Setting Circuit Diagram

Power supply sequence

Activate the digital power supply DVcc before the Vcc power supply to prevent IC malfunctions due to undefined logic in the digital circuit. Input serial data after canceling the power-on reset. When turning off the IC's power supplies, turn off Vcc and then DVcc.

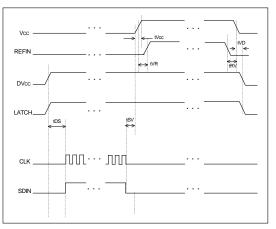


Fig. 28 Power Supply Sequence Diagram

Power supply sequence standard values

| Parameter | Symbol | | Limit | | Unit | Condition |
|--------------------------------|--------|------|-------|------|------|---------------|
| Parameter | Symbol | Min. | Тур. | Max. | Unit | Condition |
| Serial input timing | tDS | 100 | — | — | μs | Cct = 1000 pF |
| VCC activation timing | tSV | 0 | 10 | — | μs | |
| REFIN activation timing | tVR | 0 | 10 | _ | μs | |
| REFIN off timing | tRV | 0 | 10 | _ | μs | |
| Power supply off timing | tVD | 0 | 10 | _ | μs | |
| Vcc startup timing | tVCC | 1 | | — | ms | |

[BD8139AEFV]

Serial communications

The 2 wire serial control block consists of a register that stores data from the SCL and SDA pins and a DAC circuit that receives the output from this register and provides adjusted voltages to other IC blocks.

When the IC's power supply is activated, the reset function operates to set the register to a preset value.

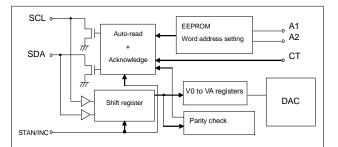


Fig. 29 2 wire serial Control Block Diagram

(1) 2 wire serial timing chart

Slave mode (SLAVE/AR = low; supports write mode only; A0 = low)

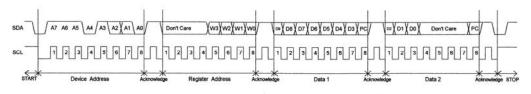


Fig. 30 2 wire serial Timing Chart (Slave)

Of device addresses A7 to A0, A7 to A3 and A0 are specific to the gamma correction voltage generation IC and should be set as follows: (A7 to A0) = 11101(A2)(A1)0.

A1 and A2 can be set externally. Because these signals are pulled down internally, they are set to 0 when in the open state. When setting them to 1, connect them to the DVcc power supply. For this reason, A1 and A2 can be used to create 4 setting combinations. When using only slave mode, a maximum of 4 BD8139AEFV ICs can be connected to the 2 wire serial line.

The lower 4 bits of the second byte are used to store the register address. The following table describes the correspondence between register addresses and amp output. The third and fourth bytes are used to store the gamma correction voltage setting. The LSB acts as a parity check bit. The method for setting the LSB is described below.

| Pogiator name | | Add | ress | | Behavior when data increases | Preset value |
|---------------|----|-----|------|----|---------------------------------|--------------|
| Register name | W3 | W2 | W1 | W0 | Benavior when data increases | Data (9:0) |
| Register 0 | 0 | 0 | 0 | 0 | V0 voltage value increases | 00_0000_0000 |
| Register 1 | 0 | 0 | 0 | 1 | V1 voltage value increases | 00_0000_0000 |
| Register 2 | 0 | 0 | 1 | 0 | V2 voltage value increases | 00_0000_0000 |
| Register 3 | 0 | 0 | 1 | 1 | V3 voltage value increases | 00_0000_0000 |
| Register 4 | 0 | 1 | 0 | 0 | V4 voltage value increases | 00_0000_0000 |
| Register 5 | 0 | 1 | 0 | 1 | V5 voltage value increases | 00_0000_0000 |
| Register 6 | 0 | 1 | 1 | 0 | V6 voltage value increases | 00_0000_0000 |
| Register 7 | 0 | 1 | 1 | 1 | V7 voltage value increases | 00_0000_0000 |
| Register 8 | 1 | 0 | 0 | 0 | V8 voltage value increases | 00_0000_0000 |
| Register 9 | 1 | 0 | 0 | 1 | V9 voltage value increases | 00_0000_0000 |
| Register A | 1 | 0 | 1 | 0 | Vcom voltage value increases | 00_0000_0000 |
| Register 0-A | 1 | 1 | 1 | 1 | V0-Vcom voltage value increases | 00_0000_0000 |

SDA serial data map

| SLAVE | mode(| SLA | VE// | AR=L) |
|-------|-------|-----|------|-------|
| | | | | |

| | First (MS | , | | | | | L | _ast (LSB) | | | |
|------|---|----------------------|---------|---|---|----------|---------|------------|--|--|--|
| Duta | | bit | | | | | | | | | |
| Byte | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 | | | |
| 1 | Device address (11101 <a2><a1>)</a1></a2> | | | | | | | 0 | | | |
| 2 | | Don | 't Care | | | Register | address | | | | |
| 3 | | data(9:3) | | | | | | PC | | | |
| 4 | | data(2:0) Don't Care | | | | | | PC | | | |
| | | <u>, , ,</u> | | 1 | | | | 1 | | | |

It needs 4 byte for slave mode.

When register address "1111", it is updated same data on all addresses.

Auto-read mode (SLAVE/AR = high)

The auto-read function enables automatic reading of the I²C bus interface's 1 kbit built-in memory. When the reset signal is cleared, automatic reads from EEPROM begin.

In auto-read mode, A1 and A2 serve as the EEPROM word address setting pins.

When A1 and A2 are both set to low, read access is available for word addresses 0 through 21.

| A2 | A1 | Read start word address | Read end word address |
|----|----|-------------------------|-----------------------|
| L | L | 0 (00h) | 21 (h) |
| Н | L | 32 (20h) | 53 (35h) |
| L | Н | 64 (40h) | 85 (55h) |
| Н | Н | 96 (60h) | 117 (75h) |

The following table describes the 22-word data format read from the EEPROM.

| Word | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 | Output | |
|------|-----------------------|-----------------------|----|------------|------------|---|----|------|--------|--|
| 1 | | | PC | 1/0 | | | | | | |
| 2 | Data (2:0) Don't Care | | | | Don't Care | | | | V0 | |
| 3 | | Data (9:3) | | | | | | PC | V1 | |
| 4 | | Data (2:0) Don't Care | | | | | | PC | VI | |
| : | | | | | : | | | | | |
| 21 | | Data (9:3) | | | | | PC | Veem | | |
| 22 | | Data (2:0 |) | Don't Care | | | | PC | Vcom | |

The first and second words are used for the V0 setting, while the third and fourth words are used for the V1 setting. Including the Vcom setting, a total of 22 words of data are read. The LSB for all words contains an even parity check (PC). The LSBs for all EPROM data settings should be set. (Where the number 1 represents an even number.)

<Example of setting for EEPROM>

| | A1=L,A2=L | | | | | | | | | | REFIN | 15 | V | |
|----|------------------------|------------|----|----|----|----|----|----|----|----|------------|------|-----------------|-------|
| | data | | | | | | | | | | | | | |
| | EEPROM WORD ADDRESS | BD8139AEFV | d7 | d6 | d5 | d4 | d3 | d2 | d1 | d0 | bin | dec | Setting voltage | |
| 1 | 00h | V0① | 1 | 1 | 1 | 0 | 0 | 1 | 0 | 0 | 1110010011 | 915 | 13.418 | V0 |
| 2 | 01h | V02 | 0 | 1 | 1 | 0 | 0 | 0 | 0 | 0 | | | | |
| 3 | 02h | V1① | 1 | 0 | 1 | 1 | 1 | 1 | 1 | 0 | 1011111010 | 762 | 11.177 | V1 |
| 4 | 03h | V1(2) | 0 | 1 | 0 | 0 | 0 | 0 | 0 | 1 | | | | |
| 5 | 04h | V2① | 1 | 0 | 1 | 0 | 1 | 0 | 1 | 0 | 1010101100 | 684 | 10.034 | V2 |
| 6 | 05h | V2(2) | 1 | 0 | 0 | 0 | 0 | 0 | 0 | 1 | | | | |
| 7 | 06h | V3① | 0 | 1 | 1 | 1 | 1 | 0 | 0 | 0 | 0111100001 | 481 | 7.061 | V3 |
| 8 | 07h | V3(2) | 0 | 0 | 1 | 0 | 0 | 0 | 0 | 1 | | | | |
| 9 | 08h | V4① | 1 | 0 | 0 | 0 | 1 | 1 | 1 | 0 | 1000111110 | 574 | 8.423 | V4 |
| 10 | 09h | V4② | 1 | 1 | 0 | 0 | 0 | 0 | 0 | 0 | | | | |
| 11 | 0Ah | V5① | 1 | 0 | 0 | 0 | 0 | 0 | 0 | 1 | 100000000 | 512 | 7.515 | V5 |
| 12 | 0Bh | V5② | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | | | | |
| 13 | 0Ch | V6① | 0 | 1 | 0 | 1 | 0 | 1 | 0 | 1 | 0101010111 | 343 | 5.039 | V6 |
| 14 | 0Dh | V6② | 1 | 1 | 1 | 0 | 0 | 0 | 0 | 1 | | | | |
| 15 | 0Eh | V7① | 0 | 1 | 0 | 1 | 1 | 1 | 1 | 1 | 0101111111 | 383 | 5.625 | V7 |
| 16 | 0Fh | V7② | 1 | 1 | 1 | 0 | 0 | 0 | 0 | 1 | | | | |
| 17 | 10h | V8① | 0 | 1 | 0 | 0 | 1 | 0 | 1 | 1 | 0100101010 | 298 | 4.380 | V8 |
| 18 | 11h | V8② | 0 | 1 | 0 | 0 | 0 | 0 | 0 | 1 | | | | |
| 19 | 12h | V9① | 0 | 0 | 0 | 1 | 1 | 1 | 1 | 0 | 0001111010 | 122 | 1.802 | V9 |
| 20 | 13h | V92 | 0 | 1 | 0 | 0 | 0 | 0 | 0 | 1 | | | | |
| 21 | 14h | VCOM(1) | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1111111111 | 1023 | 7.500 | VCOM |
| 22 | 15h | VCOM2 | 1 | 1 | 1 | 0 | 0 | 0 | 0 | 1 | | | | R1=R2 |

*Must set "1" at d7 of 16ch.

Timing Chart

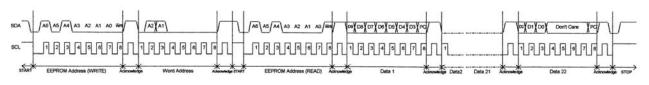


Fig. 31 2-wire serial Timing Chart (Auto-Read)

Only the EEPROM device address A3 = A2 = A1 = low is supported.

The auto-read function specifies the read start word address in EEPROM write mode. Then after resending the start signal, the data is read in read mode. When the parity check detects an error, a stop signal is sent and the auto-read function is repeated until no error is detected. If the auto-read function never completes, the EEPROM data settings should be reviewed.

• When operating in auto-read mode, a maximum of 2 BD8139AEFV ICs (A and B) can be connected to the I²C bus line. When using 2 ICs, change the CT pin capacitance value to avoid auto-read timing collisions. The following figure illustrates auto-read timing when using 2 ICs.

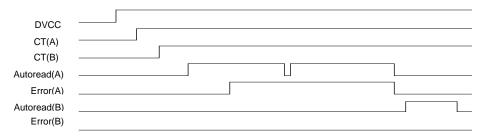
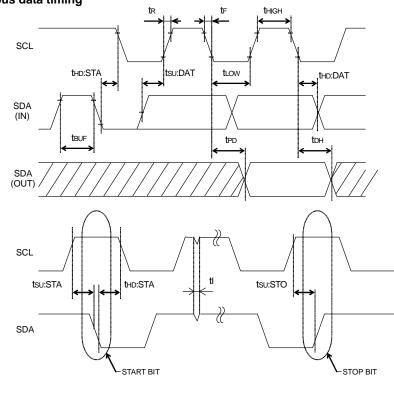


Fig 32 Auto-Read Timing Chart

Set the CT pin capacitance as follows:

Using an inappropriate capacitance setting may result in auto-read timing collisions, making it impossible to read data properly.

| BD8139AEFV | А | CT = 1000 pF | Scatter: Within 5% |
|------------|---|--------------|--------------------|
| BD8139AEFV | В | CT = 3300 pF | Scatter: Within 5% |



* SDA latches at the SCL rising edge. Fig 33

2 wire serial bus data timing

Timing standard values

| Parameter | Symbol | 2.3 | Unit | | |
|----------------------------|---------|------|-----------|-----|-----|
| | , | Min. | Min. Typ. | | |
| SCL frequency | fSCL | — | — | 400 | kHz |
| SCL high time | tHIGH | 0.6 | — | — | μs |
| SCL low time | tLOW | 1.2 | — | — | μs |
| Rise Time | tR | — | — | 0.3 | μs |
| Fall Time | tF | — | — | 0.3 | μs |
| Start condition hold time | tHD:STA | 0.6 | — | — | μs |
| Start condition setup time | tSU:STA | 0.6 | — | — | μs |
| SDA hold time | tHD:DAT | 100 | — | — | ns |
| SDA setup time | tSU:DAT | 100 | — | — | ns |
| Acknowledge delay time | tPD | 0.1 | — | 0.9 | μs |
| Acknowledge hold time | tDH | 0.1 | _ | _ | μs |
| Stop condition setup time | tSU:STO | 0.6 | — | — | μs |
| Bus release time | tBUF | 1.2 | — | — | μs |

Power supply sequence

Activate the digital power supply DVcc before the Vcc power supply to prevent IC malfunctions due to undefined logic in the digital circuit. Input serial data after canceling the power-on reset. When turning off the IC's power supplies, turn off Vcc and then DVcc.

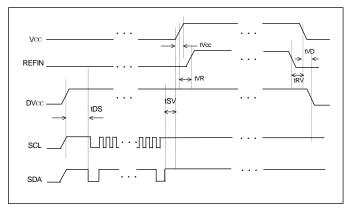


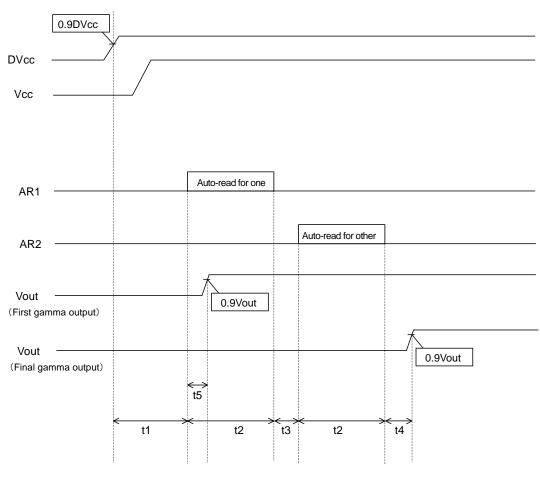
Fig. 34 Power Supply Sequence Diagram

Power supply sequence standard values

| Parameter | Symbol | Limit | | | Unit | Condition |
|--------------------------------|--------|-------|------|------|------|---------------|
| Falameter | Symbol | Min. | Тур. | Max. | Unit | Condition |
| Serial input timing | tDS | 100 | — | — | μs | Cct = 1000 pF |
| Vcc activation timing | tSV | 0 | 10 | — | μs | |
| REFIN activation timing | tVR | 0 | 10 | — | μs | |
| REFIN off timing | tRV | 0 | 10 | — | μs | |
| Power supply off timing | tVD | 0 | 10 | — | μs | |
| Vcc startup timing | tVcc | 1 | — | — | ms | |

•Closing time for auto-read

(Input Vcc ~ Beginning auto-read ~ Taking time for auto-read, when 2use.)





Time from input Vcc until final gamma output

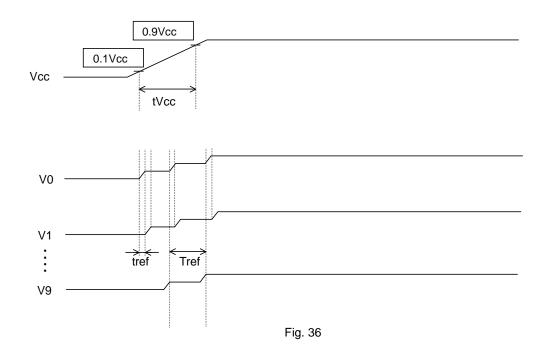
| $t total1 = t1 + t2 \times 2 + t3 + t4$ | | | | | | | | | |
|---|------|------|-------------|--|--|--|--|--|--|
| | min. | typ. | max | | | | | | |
| t1 | 108 | 169 | 240 | | | | | | |
| t2 | 730 | 1160 | 1660 | | | | | | |
| t3 | 156 | 248 | 356 | | | | | | |
| t4 | - | - | 145 | | | | | | |
| t total | 1724 | 2737 | 4061 | | | | | | |
| | | | Unit : µsec | | | | | | |

Time from input voltage until first gamma output (condition of input Vcc already) t total2 = t1 + t5

| | min. | typ. | max |
|---------|------|------|-------------|
| t1 | 108 | 169 | 240 |
| t5 | 194 | 308 | 442 |
| t total | 302 | 477 | 682 |
| | | | Unit : µsec |

%CT1=1000pF, CT2=3300pF, scatter within 5%

•When it inputs Vcc, it outputted the gamma output voltage.



DAC 1ch supports all gamma output amps by sample/hold function. So, each amp operates reflesh by Tref.

| | Min. | Тур. | Max. |
|------|------|------|-------------|
| Tref | 63 | 101 | 145 |
| | | | Unit : µsec |

Reflesh time of each amp is following.

tref = Tref / 11ch

Under condition of the small difference between setting voltage of amp and slew rate of Vcc is fast, when it inputs Vcc, it is possible that output voltage come from behind next output voltage.

$$\begin{cases} V0 = VDAC \times 2 \times \frac{n0+1}{1024} & (n0 : Setting voltage of 10bit) \\ V1 = VDAC' \times 2 \times \frac{n1+1}{1024} & VDAC' = VDAC + \frac{SR}{2} \times tref & (SR : Slew rate of Vcc) \end{cases}$$

Condition of non-reverse-voltage is following V0-V1>0

$$\frac{n0+1}{n1+1} > 1 + \frac{SR \times tref}{2VDAC}$$

Under condition of the big difference between output voltage or slew rate of Vcc is slow, reverse-voltage don't occur much. Worst condition is following.

n0 / n1 > 1.0469

Notice that the setting voltage between V0 and V1 is within 720mV. It is possible for reverse of voltage in transition.

Input equivalent circuit diagrams

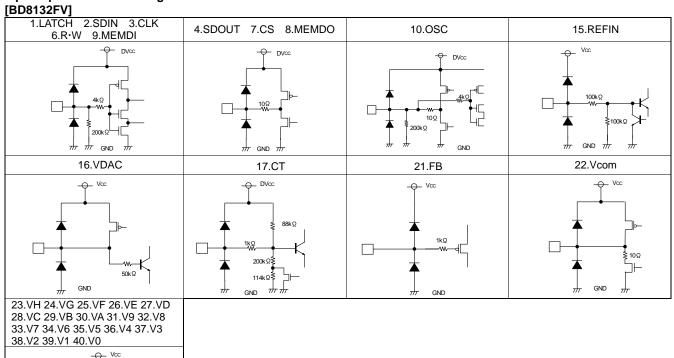
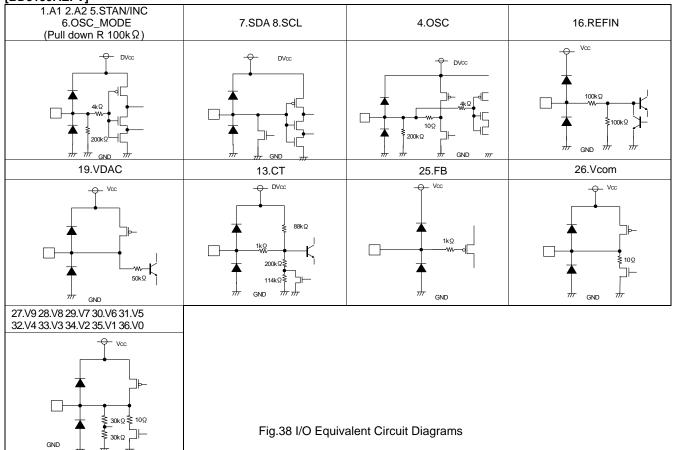


Fig.37 I/O Equivalent Circuit Diagrams

[BD8139AEFV]

30k Q ≹ 10Ω

_{30kΩ} 귀



Notes for use

1) Absolute maximum ratings

Use of the IC in excess of absolute maximum ratings such as the applied voltage or operating temperature range may result in IC damage. Assumptions should not be made regarding the state of the IC (short mode or open mode) when such damage is suffered. A physical safety measure such as a fuse should be implemented when use of the IC in a special mode where the absolute maximum ratings may be exceeded is anticipated.

2) GND potential

Ensure a minimum GND pin potential in all operating conditions.

3) Setting of heat

Use a thermal design that allows for a sufficient margin in light of the power dissipation (Pd) in actual operating conditions.

4) Pin short and mistake fitting

Use caution when orienting and positioning the IC for mounting on printed circuit boards. Improper mounting may result in damage to the IC. Shorts between output pins or between output pins and the power supply and GND pins caused by the presence of a foreign object may result in damage to the IC.

5) Actions in strong magnetic field

Use caution when using the IC in the presence of a strong magnetic field as doing so may cause the IC to malfunction.

6) Testing on application boards

When testing the IC on an application board, connecting a capacitor to a pin with low impedance subjects the IC to stress. Always discharge capacitors after each process or step. Ground the IC during assembly steps as an antistatic measure, and use similar caution when transporting or storing the IC. Always turn the IC's power supply off before connecting it to or removing it from a jig or fixture during the inspection process.

7) Ground wiring patterns

When using both small signal and large current GND patterns, it is recommended to isolate the two ground patterns, placing a single ground point at the application's reference point so that the pattern wiring resistance and voltage variations caused by large currents do not cause variations in the small signal ground voltage. Be careful not to change the GND wiring patterns of any external components.

8) Regarding input pin of the IC

This monolithic IC contains P+ isolation and P substrate layers between adjacent elements in order to keep them isolated. P/N junctions are formed at the intersection of these P layers with the N layers of other elements to create a variety of parasitic elements.For example, when the resistors and transistors are connected to the pins as shown in Fig.39, a parasitic diode or a transistor operates by inverting the pin voltage and GND voltage.The formation of parasitic elements as a result of the relationships of the potentials of different pins is an inevitable result of the IC's architecture. The operation of parasitic elements can cause interference with circuit operation as well as IC malfunction and damage. For these reasons, it is necessary to use caution so that the IC is not used in a way that will trigger the operation of parasitic elements, such as the application of voltages lower than the GND (P substrate) voltage to input and output pins.

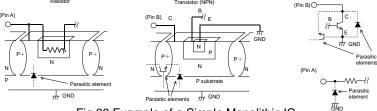


Fig.39 Example of a Simple Monolithic IC

9) Overcurrent protection circuits

An overcurrent protection circuit designed according to the output current is incorporated for the prevention of IC damage that may result in the event of load shorting. This protection circuit is effective in preventing damage due to sudden and unexpected accidents. However, the IC should not be used in applications characterized by the continuous operation or transitioning of the protection circuits. At the time of thermal designing, keep in mind that the current capacity has negative characteristics to temperatures.

10) TSD (Thermal shutdown) circuit

This IC incorporates a built-in TSD circuit for the protection from thermal destruction. The IC should be used within the specified power dissipation range. However, in the event that the IC continues to be operated in excess of its power dissipation limits, the attendant rise in the chip's junction temperature Tj will trigger the TSD circuit to turn off all output power elements. The circuit automatically resets once the junction temperature Tj drops.

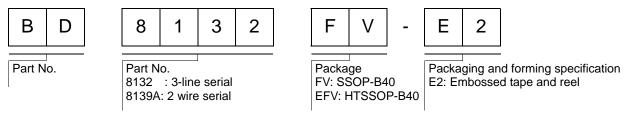
Operation of the TSD circuit presumes that the IC's absolute maximum ratings have been exceeded. Application designs should never make use of the TSD circuit.

11) Testing on application boards

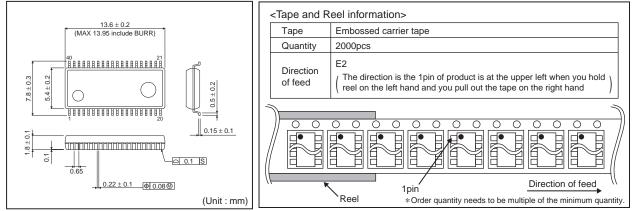
At the time of inspection of the installation boards, when the capacitor is connected to the pin with low impedance, be sure to discharge electricity per process because it may load stresses to the IC. Always turn the IC's power supply off before connecting it to or removing it from a jig or fixture during the inspection process. Ground the IC during assembly steps as an antistatic measure, and use similar caution when transporting or storing the IC.

BD8132FV, BD8139AEFV

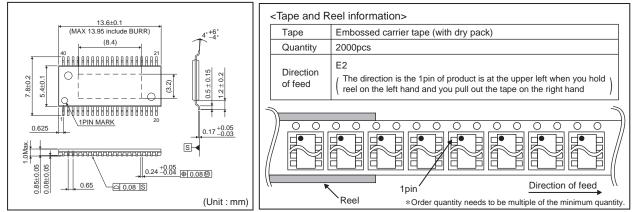
Ordering part number



SSOP-B40



HTSSOP-B40



Notice

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| CLASSⅣ | | CLASSⅢ | |

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 - [a] Installation of protection circuits or other protective devices to improve system safety
 - [b] Installation of redundant circuits to reduce the impact of single or multiple circuit failure
- 3. Our Products are designed and manufactured for use under standard conditions and not under any special or extraordinary environments or conditions, as exemplified below. Accordingly, ROHM shall not be in any way responsible or liable for any damages, expenses or losses arising from the use of any ROHM's Products under any special or extraordinary environments or conditions. If you intend to use our Products under any special or extraordinary environments or conditions (as exemplified below), your independent verification and confirmation of product performance, reliability, etc, prior to use, must be necessary:
 - [a] Use of our Products in any types of liquid, including water, oils, chemicals, and organic solvents
 - [b] Use of our Products outdoors or in places where the Products are exposed to direct sunlight or dust
 - [C] Use of our Products in places where the Products are exposed to sea wind or corrosive gases, including Cl₂, H₂S, NH₃, SO₂, and NO₂
 - [d] Use of our Products in places where the Products are exposed to static electricity or electromagnetic waves
 - [e] Use of our Products in proximity to heat-producing components, plastic cords, or other flammable items
 - [f] Sealing or coating our Products with resin or other coating materials
 - [g] Use of our Products without cleaning residue of flux (even if you use no-clean type fluxes, cleaning residue of flux is recommended); or Washing our Products by using water or water-soluble cleaning agents for cleaning residue after soldering
 - [h] Use of the Products in places subject to dew condensation
- 4. The Products are not subject to radiation-proof design.
- 5. Please verify and confirm characteristics of the final or mounted products in using the Products.
- 6. In particular, if a transient load (a large amount of load applied in a short period of time, such as pulse. is applied, confirmation of performance characteristics after on-board mounting is strongly recommended. Avoid applying power exceeding normal rated power; exceeding the power rating under steady-state loading condition may negatively affect product performance and reliability.
- 7. De-rate Power Dissipation (Pd) depending on Ambient temperature (Ta). When used in sealed area, confirm the actual ambient temperature.
- 8. Confirm that operation temperature is within the specified range described in the product specification.
- 9. ROHM shall not be in any way responsible or liable for failure induced under deviant condition from what is defined in this document.

Precaution for Mounting / Circuit board design

- 1. When a highly active halogenous (chlorine, bromine, etc.) flux is used, the residue of flux may negatively affect product performance and reliability.
- 2. In principle, the reflow soldering method must be used; if flow soldering method is preferred, please consult with the ROHM representative in advance.

For details, please refer to ROHM Mounting specification

Precautions Regarding Application Examples and External Circuits

- 1. If change is made to the constant of an external circuit, please allow a sufficient margin considering variations of the characteristics of the Products and external components, including transient characteristics, as well as static characteristics.
- 2. You agree that application notes, reference designs, and associated data and information contained in this document are presented only as guidance for Products use. Therefore, in case you use such information, you are solely responsible for it and you must exercise your own independent verification and judgment in the use of such information contained in this document. ROHM shall not be in any way responsible or liable for any damages, expenses or losses incurred by you or third parties arising from the use of such information.

Precaution for Electrostatic

This Product is electrostatic sensitive product, which may be damaged due to electrostatic discharge. Please take proper caution in your manufacturing process and storage so that voltage exceeding the Products maximum rating will not be applied to Products. Please take special care under dry condition (e.g. Grounding of human body / equipment / solder iron, isolation from charged objects, setting of lonizer, friction prevention and temperature / humidity control).

Precaution for Storage / Transportation

- 1. Product performance and soldered connections may deteriorate if the Products are stored in the places where:
 - [a] the Products are exposed to sea winds or corrosive gases, including Cl2, H2S, NH3, SO2, and NO2
 - [b] the temperature or humidity exceeds those recommended by ROHM
 - [c] the Products are exposed to direct sunshine or condensation
 - [d] the Products are exposed to high Electrostatic
- 2. Even under ROHM recommended storage condition, solderability of products out of recommended storage time period may be degraded. It is strongly recommended to confirm solderability before using Products of which storage time is exceeding the recommended storage time period.
- 3. Store / transport cartons in the correct direction, which is indicated on a carton with a symbol. Otherwise bent leads may occur due to excessive stress applied when dropping of a carton.
- 4. Use Products within the specified time after opening a humidity barrier bag. Baking is required before using Products of which storage time is exceeding the recommended storage time period.

Precaution for Product Label

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